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#### November 2013

# FDMS037N08B N-Channel PowerTrench<sup>®</sup> MOSFET 75 V, 100 A, 3.7 m $\Omega$

## Features

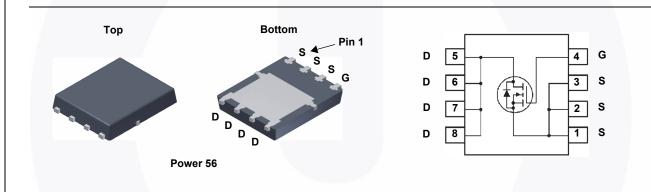
- R<sub>DS(on)</sub> = 3.01 mΩ (Typ.) @ V<sub>GS</sub> = 10 V, I<sub>D</sub> = 50 A
- Low FOM R<sub>DS(on)</sub>\*Q<sub>G</sub>
- Low Reverse Recovery Charge, Q<sub>rr</sub> = 80 nC
- Soft Reverse Recovery Body Diode
- Enables Highly Efficiency in Synchronous Rectification
- Fast Switching Speed
- 100% UIL Tested
- RoHS Compliant

# Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advance PowerTrench<sup>®</sup> process that has been tailored to minimize the on-state resistance while maintaining superior switching performance.

## Applications

- · Synchronous Rectification for ATX / Server / Telecom PSU
- Battery Protection circuit
- DC Motor Drives and Uninterruptible Power Supplies



## MOSFET Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted.

	U A					
Symbol		FDMS037N08B	Unit			
V <sub>DSS</sub>	Drain to Source Voltage			75	V	
V <sub>GSS</sub>	Gate to Source Voltage			±20	V	
I <sub>D</sub>		- Continuous (T <sub>C</sub> = 25 <sup>o</sup> C)	100			
	Drain Current	- Continuous (T <sub>C</sub> = 25°C, Silio	128	А		
		- Continuous ( $T_A = 25^{\circ}C$ )	(Note 1a)	19.9		
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 2)	400	А	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	·	(Note 3)	180.6	mJ	
P <sub>D</sub>	Dower Discipation	(T <sub>C</sub> = 25 <sup>o</sup> C)		104.2	W	
	Power Dissipation	$(T_A = 25^{\circ}C)$	(Note 1a)	0.83	W	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperatu		-55 to +150	°C		

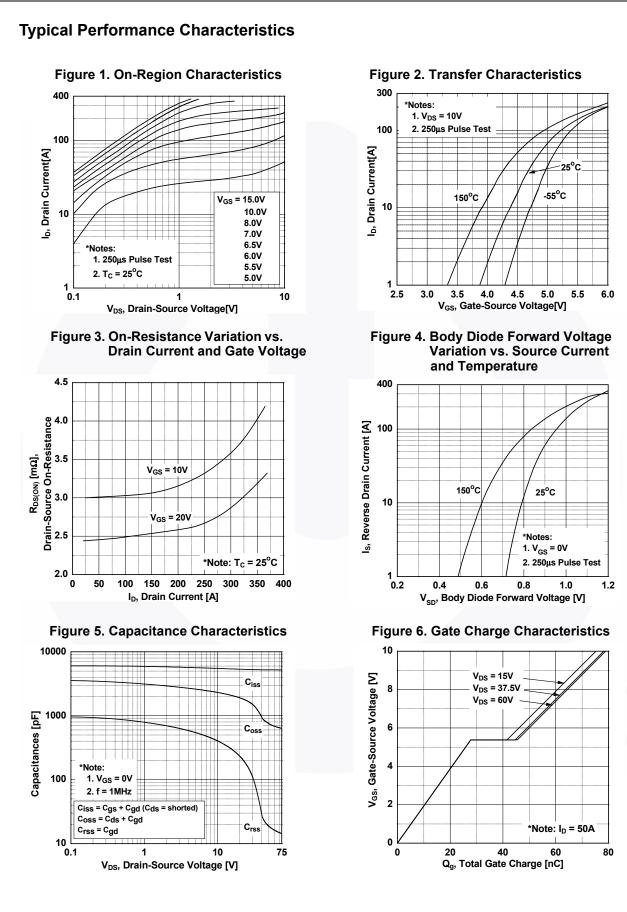
# **Thermal Characteristics**

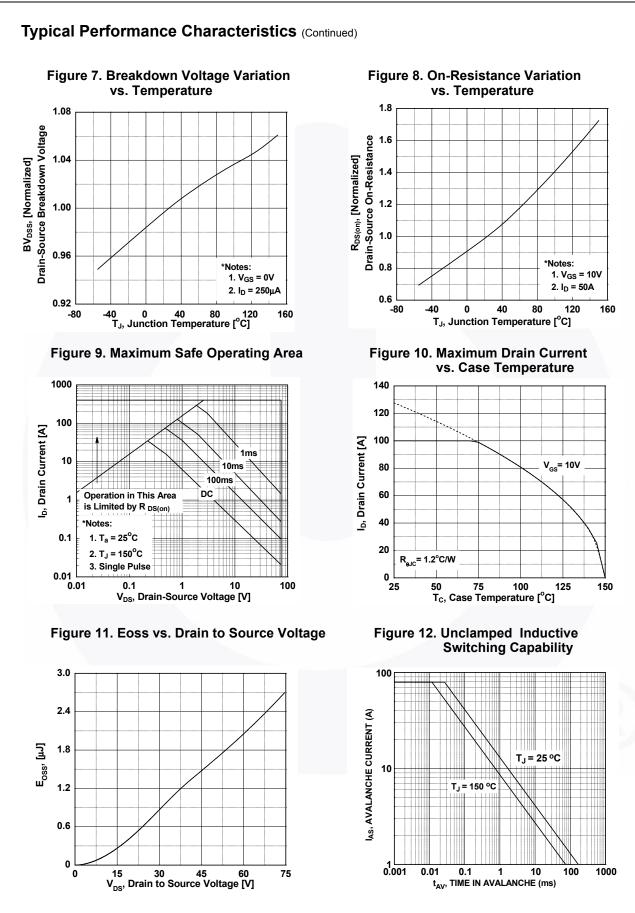
Symbol	Parameter	FDMS037N08B	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	1.2	°C/W
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction to Ambient, Max. (Note 1a)	50	°C/W

108B FDI		Packa	ge	Reel Size	Tape	e Width		Quantit	iy 🛛
	FDMS037N08B FDMS037N08B Powe			r 56 13 " 12		l2 mm		3000 units	
Characte	eristics TJ= 2	25°C unless	otherwise	e noted					
	Parameter			Test Conditions		Min.	Тур.	Max.	Unit
eristics									
			$I_{\rm D} = 250 \mu A V_{\rm CO} = 0 V$			75	-	-	V
	•				-			-	
Coefficient	<b>e</b>		5			-	39	-	mV/ºC
Zero Gate Vol	÷		V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V			-	-	1	μA
Gate to Body	Body Leakage Current			$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			-	±100	nA
eristics									
Gate Threshold Voltage			V <sub>GS</sub> = V <sub>DS</sub> . I <sub>D</sub> = 250 µA			2.5	-	4.5	V
Static Drain to						-	3.01	3.7	mΩ
Forward Trans	d Transconductance					-	108	-	S
aracteristi	22								
						_	4550	5915	pF
			V <sub>DS</sub> = 37.5 V, V <sub>GS</sub> = 0 V f = 1 MHz		-				pF
					-				pF
			V <sub>DS</sub> =	37.5 V. V <sub>GS</sub> = 0 V		-		-	pF
			03			-	76.8	100	nC
	-		V <sub>DS</sub> =	37.5 V, I <sub>D</sub> = 50 A	-	-	27.5	-	nC
	-		$V_{GS} = 0 V \text{ to } 10 V$			-	17.4	-	nC
Gate Plateau	Volatge		-		(Note 4)	-	5.1	-	V
Total Gate Ch	arge Sync.		V <sub>DS</sub> =	0 V, I <sub>D</sub> = 50 A	, ,	-	66.3	-	nC
Output Charge	e		V <sub>DS</sub> =	37.5 V, V <sub>GS</sub> = 0 V		-	74.6	-	nC
Equivalent Se	ries Resistance		f = 1 N	1Hz		-	1.28	-	Ω
Characteris <sup>®</sup>	tics								
						-	34.9	80	ns
,	,		$V_{DD}$ = 37.5 V, I <sub>D</sub> = 50 A V <sub>GS</sub> = 10 V, R <sub>G</sub> = 4.7 Ω		-	-			ns
	-				-	_	55.3	120	ns
5					(Note 4)	-	19.4	49	ns
Diada Cl					(		-		_
1									
							-		A
						-	-		A
		Voltage					-	1.3	V
	•							-	ns
Reverse Reco	very Charge		uiF/ut -	- 100 Α/μ5		-	84	-	nC
	Drain to Sourd Breakdown Vo Coefficient Zero Gate Vol Gate to Body eristics Gate Thresho Static Drain to Forward Trans haracteristic Input Capacita Output Capac Reverse Trans Energy Relete Total Gate Cha Gate to Drain Gate to Sourc Gate to Drain Gate Plateau Total Gate Cha Output Charge Equivalent Se Characterist Turn-On Delay Turn-Off Delay Turn-Off Fall T ce Diode Ch Maximum Con Maximum Puls Drain to Sourc Reverse Reco	Drain to Source Breakdown Vo Breakdown Voltage Temperatu Coefficient Zero Gate Voltage Drain Curre Gate to Body Leakage Current eristics Gate Threshold Voltage Static Drain to Source On Resi Forward Transconductance haracteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Energy Releted Output Capaci Total Gate Charge at 10V Gate to Source Gate Charge Gate Drain "Miller" Charge Gate Plateau Volatge Total Gate Charge Sync. Output Charge Equivalent Series Resistance Enury Capacitance Bate Charge Sync. Output Charge Equivalent Series Resistance Characteristics Turn-On Delay Time Turn-Off Delay Time Turn-Off Fall Time Ce Diode Characteristics Maximum Continuous Drain to Maximum Pulsed Drain to Sour	Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Body Leakage Current eristics Gate Threshold Voltage Static Drain to Source On Resistance Forward Transconductance haracteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Energy Releted Output Capacitance Total Gate Charge at 10V Gate to Source Gate Charge Gate to Drain "Miller" Charge Gate to Drain "Miller" Charge Gate Plateau Volatge Total Gate Charge Sync. Output Charge Equivalent Series Resistance Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Fall Time Ce Diode Characteristics Maximum Continuous Drain to Source Diode Maximum Pulsed Drain to Source Diode Forward Voltage Reverse Recovery Time	Drain to Source Breakdown Voltage $I_D = 25$ Breakdown Voltage Temperature Coefficient $I_D = 25$ Zero Gate Voltage Drain Current $V_{DS} =$ Gate to Body Leakage Current $V_{GS} =$ eristicsImage: Static Drain to Source On Resistance $V_{GS} =$ Static Drain to Source On Resistance $V_{GS} =$ Forward Transconductance $V_{DS} =$ haracteristicsInput Capacitance $V_{DS} =$ Output Capacitance $V_{DS} =$ fotal Gate Charge at 10V $V_{DS} =$ Gate to Source Gate Charge $V_{DS} =$ Total Gate Charge at 10V $V_{DS} =$ Gate Plateau Volatge $V_{DS} =$ Output Charge $V_{DS} =$ Output Charge $V_{DS} =$ Gate Plateau Volatge $V_{DS} =$ Total Gate Charge Sync. $V_{DS} =$ Output Charge $V_{DS} =$ Turn-On Delay Time $V_{DS} =$ Turn-Off Delay Time $V_{GS} =$ Turn-Off Fall Time $V_{GS} =$ Maximum Continuous Drain to Source Diode Forward CuDrain to Source Diode Forward Voltage $V_{GS} =$ Reverse Recovery Time $V_{GS} =$	Drain to Source Breakdown Voltage $I_D = 250 \ \mu$ A, $V_{GS} = 0 \ V$ Breakdown Voltage Temperature Coefficient $I_D = 250 \ \mu$ A, Referenced to $I_D = 250 \ \mu$ A, Referenced to Zero Gate Voltage Drain Current $V_{DS} = 60 \ V, V_{GS} = 0 \ V$ Zero Gate Voltage Drain Current $V_{DS} = 60 \ V, V_{DS} = 0 \ V$ Gate to Body Leakage Current $V_{GS} = \pm 20 \ V, V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{GS} = \pm 20 \ V, V_{DS} = 0 \ V$ Forward Transconductance $V_{GS} = 10 \ V, I_D = 50 \ A$ Forward Transconductance $V_{DS} = 10 \ V, I_D = 50 \ A$ Forward Transconductance $V_{DS} = 37.5 \ V, V_{GS} = 0 \ V$ Input Capacitance $V_{DS} = 37.5 \ V, V_{GS} = 0 \ V$ F = 1 \ MHzReverse Transfer Capacitance $V_{DS} = 37.5 \ V, V_{GS} = 0 \ V$ Energy Releted Output Capacitance $V_{DS} = 37.5 \ V, V_{GS} = 0 \ V$ Gate to Source Gate Charge $V_{DS} = 0 \ V, I_D = 50 \ A$ Gate to Drain "Miller" Charge $V_{DS} = 0 \ V, I_D = 50 \ A$ Output Charge $V_{DS} = 37.5 \ V, V_{GS} = 0 \ V$ Gate Charge Sync. $V_{DS} = 37.5 \ V, V_{GS} = 0 \ V$ Gate Charge Sync. $V_{DS} = 37.5 \ V, V_{GS} = 0 \ V$ Equivalent Series Resistancef = 1 \ MHzCharacteristicsTurn-On Delay Time Turn-Off Delay TimeTurn-Off Delay Time Turn-Off Fall Time $V_{CS} = 0 \ V, I_S = 50 \ A$ Maximum Continuous Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentDrain to Source Diode Forward VoltageV_{G	Drain to Source Breakdown VoltageID $= 250 \mu A, V_{GS} = 0 V$ Breakdown Voltage Temperature CoefficientID $= 250 \mu A, Referenced to 25^{\circ}C$ Zero Gate Voltage Drain CurrentVDS $= 60 V, V_{GS} = 0 V$ Gate to Body Leakage CurrentVDS $= 60 V, V_{DS} = 0 V$ eristicsGate Threshold VoltageVGS $= 120 V, V_{DS} = 0 V$ eristicsGate Threshold VoltageVGS $= 10 V, ID = 50 A$ Forward TransconductanceVDS $= 10 V, ID = 50 A$ NotarceristicsInput CapacitanceVDS $= 37.5 V, V_{GS} = 0 V$ Output CapacitanceVDS $= 37.5 V, V_{GS} = 0 V$ Energy Releted Output CapacitanceVDS $= 37.5 V, V_{GS} = 0 V$ Gate to Source Gate ChargeVDS $= 37.5 V, ID = 50 A$ Gate to Drain "Miller" ChargeVDS $= 0 V, ID = 50 A$ Gate to Charge Sync.VDS $= 0 V, ID = 50 A$ Output ChargeVDS $= 37.5 V, ID = 50 A$ Qutput ChargeVDS $= 37.5 V, ID = 50 A$ Output ChargeVDS $= 37.5 V, ID = 50 A$ Output ChargeVDS $= 37.5 V, ID = 50 A$ Output ChargeVDS $= 37.5 V, ID = 50 A$ Turn-On Rise TimeVDS $= 10 V, RG = 4.7 \Omega$ Turn-Off Delay TimeVDS $= 37.5 V, ID = 50 A$ Turn-Off Fall Time(Note 4)Characteristics $V_{OS} = 10 V, RG = 4.7 \Omega$ Maximum Continuous Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward C	$\begin{array}{ c c c c } \mbox{Drain to Source Breakdown Voltage} & I_D = 250 \ \mu A, \ V_{GS} = 0 \ V & 75 \\ \mbox{Breakdown Voltage Temperature} & I_D = 250 \ \mu A, \ Referenced to 25^{\circ}C & - \\ \mbox{Coefficient} & V_{DS} = 60 \ V, \ V_{GS} = 0 \ V & - \\ \mbox{Gate to Body Leakage Current} & V_{DS} = 60 \ V, \ V_{GS} = 0 \ V & - \\ \mbox{Cate to Body Leakage Current} & V_{GS} = \pm 20 \ V, \ V_{DS} = 0 \ V & - \\ \mbox{eristics} & & & & & & & & & & & & & & & & & & &$	$\begin{array}{c c c c c c c c c c c c c c c c c c c $	$\begin{array}{ c c c c c } \mbox{Drain to Source Breakdown Voltage} & I_{D} = 250 \ \mu A, V_{GS} = 0 \ V & 75 & - & - \\ \mbox{Breakdown Voltage Temperature} & I_{D} = 250 \ \mu A, Referenced to 25^{\circ}C & - & 39 & - \\ \mbox{Zero Gate Voltage Drain Current} & V_{DS} = 60 \ V, V_{GS} = 0 \ V & - & - & 1 \ 1 \ \mbox{Gate to Body Leakage Current} & V_{GS} = \pm 20 \ V, V_{DS} = 0 \ V & - & - & \pm 100 \ \end{tabular}$

3. L = 0.3 mH, I<sub>AS</sub> = 34.7 A, starting T<sub>J</sub> = 25°C. 4. Essentially independent of operating temperature typical characteristics.

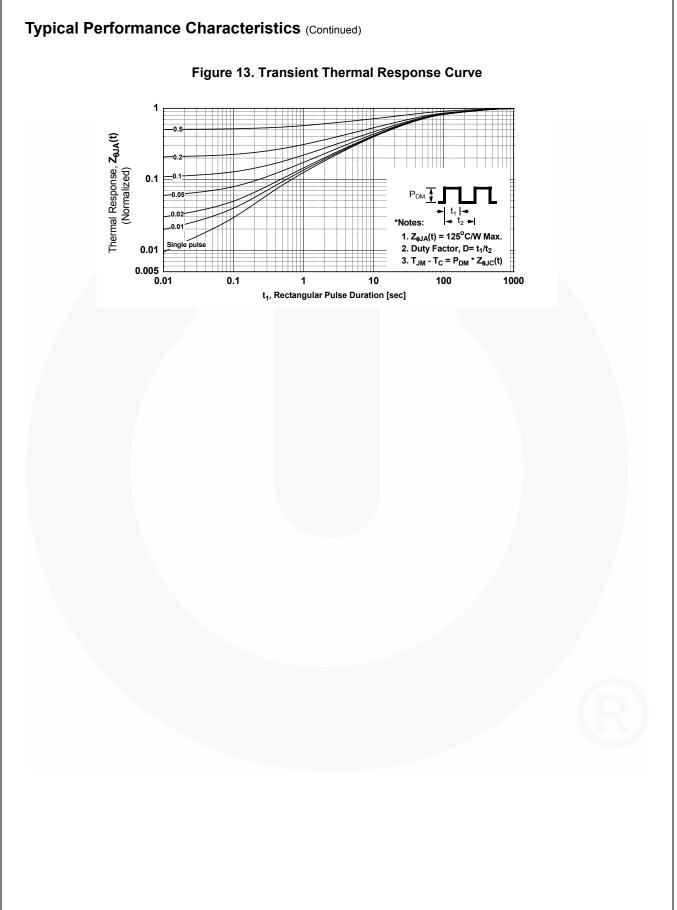
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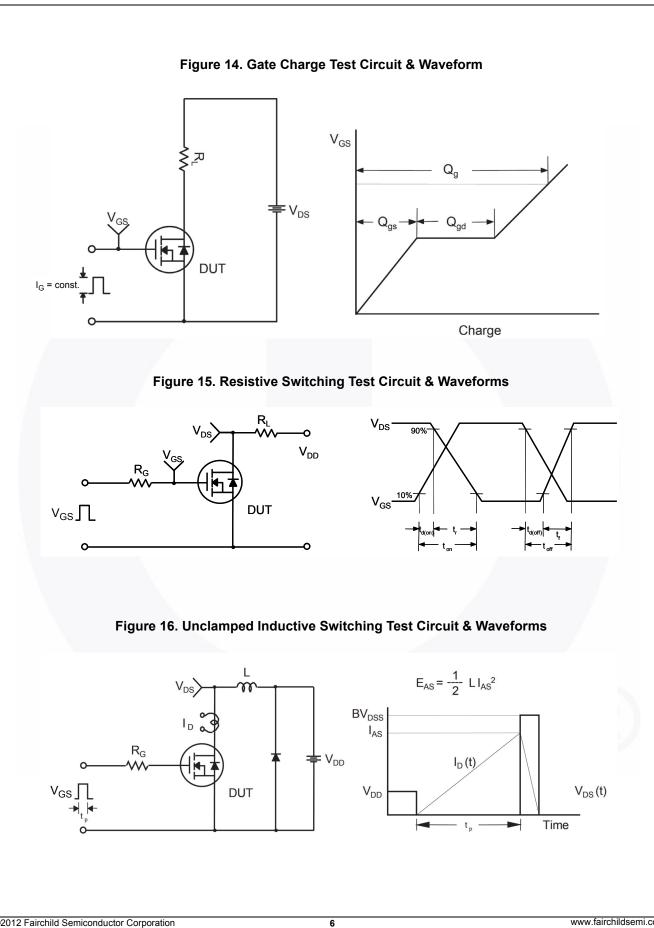


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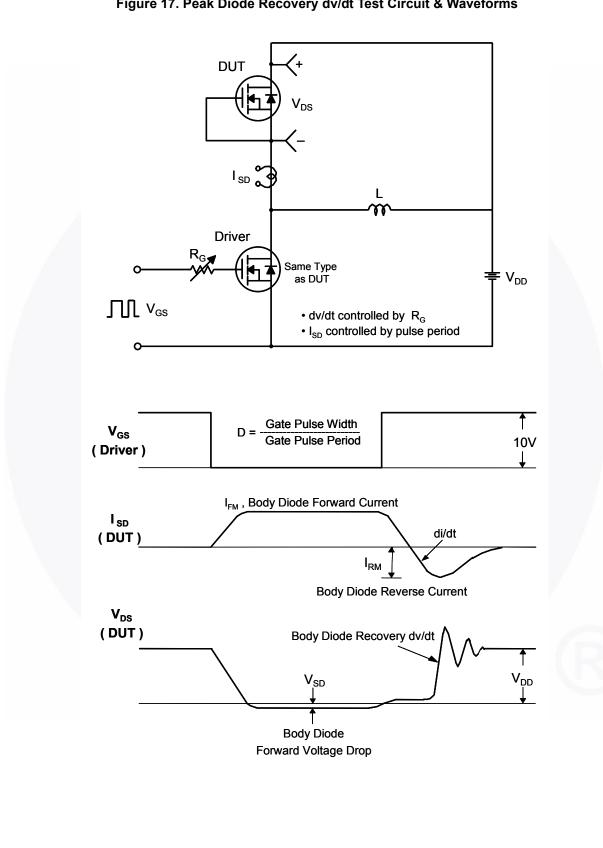
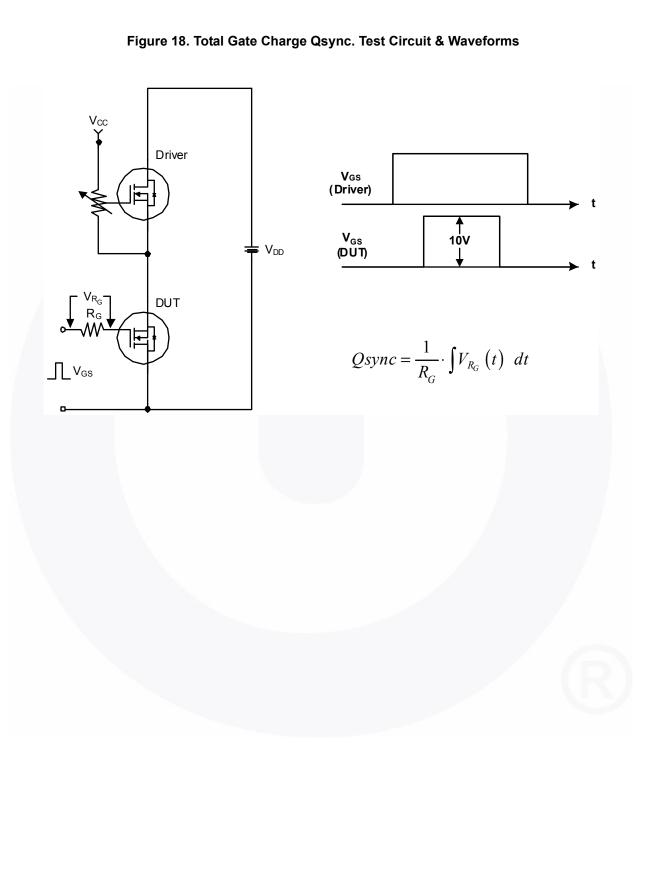
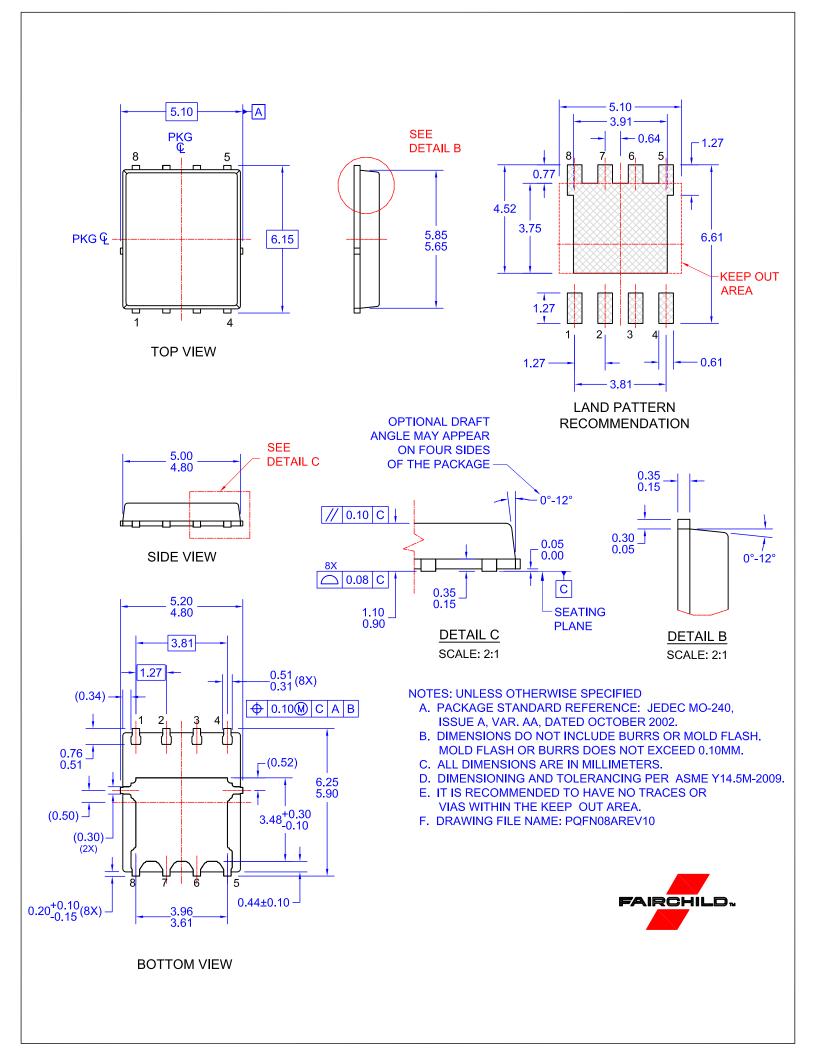


Figure 17. Peak Diode Recovery dv/dt Test Circuit & Waveforms







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